

# Review on Vanadium Pentoxide Thin Films Coated by Varying Thickness and Temperatures and Their Obtained Bandgaps

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**Abstract:** - In the past decade delectable properties and the utilization of vanadium pentoxide thin films have attracted the attention of most researchers. An important role of  $V_2O_5$  thin film applications, namely cathode material for Li batteries, gas sensors, transistors, resistance (in the form of thin film) and catalysts. This review summarizes the list of a few preparation methods of thin films known till now and different thickness of films, temperature and obtained bandgap from different methods.

**Keywords:** Vanadium pentoxide, vacuum evaporation method, electron beam evaporation, pulsed laser deposition, thickness and temperature.

## I. INTRODUCTION

An engrossing property of vanadium is more than one stable multiple oxide state and the order of oxide compounds is  $VO_2, V_2O_5, VO, V_2O_3$ [1-3]. Vanadium pentoxide has certain convenient properties such as thermo-electro

chromic behavior, conducting to semiconducting transition and high co-efficient resistance. The wide range of applications of vanadium oxide are optoelectronic device, optical switches, gas sensors and smart windows[1-6]. Well-known vanadium pentoxide manifests insulator to conduct phase transition at the temperature of  $257^\circ\text{C}$ [7]. N-type semiconducting  $V_2O_5$  has 2.3 eV [8].  $V_2O_5$  comes under orthorhombic structure unit cell, and the values of lattice parameters a, b, c are ( $11.510\text{\AA}$ ,  $3.563\text{\AA}$  and  $4.369\text{\AA}$ )[9]. The prepared  $V_2O_5$  thin films recruit from a few techniques, namely electron beam evaporation, thermal vacuum evaporation, reactive sputtering, pulsed laser deposition and sol-gel (dip-coating). Amorphous and polycrystalline vanadium have been investigated [10-12].  $V_2O_5$  is a premium catalyst as a chemical[13]. The shared corners, faces, edges of pentagonal by pyramids, tetrahedral, octahedral and square pyramids are combined to form an excellent variety of structural arrangements [9]

. Table 1. Different methods of  $V_2O_5$  thin films

Methods	Application area	Temperature ( $^\circ\text{C}$ )	Thickness (nm)	Band gap energy (eV)	Transmittance (in %)
Thermal vacuum evaporation[15]	Thin film batteries	Room Temperature	110	2.40	Not studied
			195	2.35	
			256	2.15	
			365	2.02	
Electron beam Evaporation [21]	Electronic Device	0	62	2.9	Not studied
		573	99	2.78	
		673	46	2.82	
		773	48	2.78	
Electron beam Evaporation [19]	Optical switching	200	200-2500	2.79	Not studied
		250		2.71	
		300		2.64	
		350		2.53	
		400		2.48	
		450		2.30	
500	1.87				
Electron beam Evaporation [22]	Energy efficient surface	Not studied	50	Not studied	0.840 ( $T_{\text{luminous}}$ )
			75		0.787 ( $T_{\text{solar}}$ )
			175		0.829 ( $T_{\text{luminous}}$ ) 0.765 ( $T_{\text{solar}}$ ), 0.762 ( $T_{\text{luminous}}$ ), 0.719 ( $T_{\text{solar}}$ )
Vacuum evaporation[14]	Cathode materials for TFBS	300 & 400	300-1100	Not studied	70 60 45(vis region)

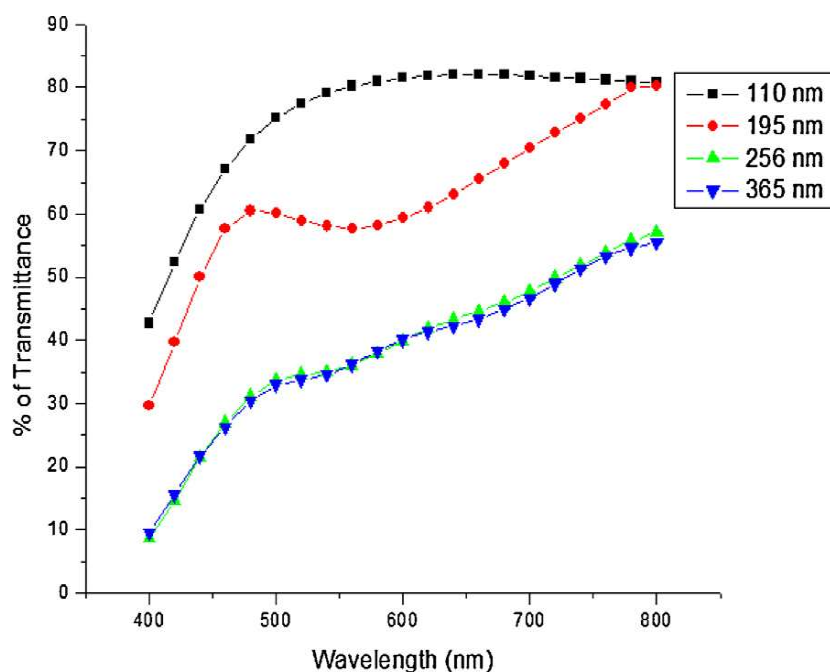
Pulsed laser Deposition[9]	Nano electronics	220 (substrate)	100	2.53	Not studied
Thermal evaporation [21]	Thermo electric property	500 (post annealing)	<100	2.8	> 60

## II. PREPARATION METHOD OF $V_2O_5$ THIN FILMS

### 2.1 Vacuum evaporation technique

Nowadays thermal evaporation method is widely used to prepare  $V_2O_5$  thin films. Vanadium is a stable multiple oxide having more than one state and VO,  $VO_2$ ,  $VO_3$ ,  $V_2O_5$  are oxide forms. Aqueous electrolytes present in conventional bulk batteries are involved in charge and discharge process and it is responsible for the formation of dendrite phases, which are not

present in TFBs[14].  $V_2O_5$  has high capacity, good cycle performance, high energy density and high potential, so it is a delectable candidate for TFBs[14]. The properties of vanadium pentoxide films are mostly dependent on deposition conditions, namely deposition temperature, vacuum, residual gases in the chamber during the deposition process and deposition rate as well as deposition technique[14]. Transmittance of  $V_2O_5$  thin films decrease with the increase in its thickness [15].



Ref[15]:Sengodan Raja, Gopal subramani, Dinesh Bheeman, Ranjithkumar Rajamani, ChandarShekar Bellan, Structural and Opitcal properties of vacuum evaporated  $V_2O_5$  thin films, Optik 127(2016)461.

Fig.1: Transmittance spectral analysis of vanadium pentoxide films deposited at various thicknesses [15].

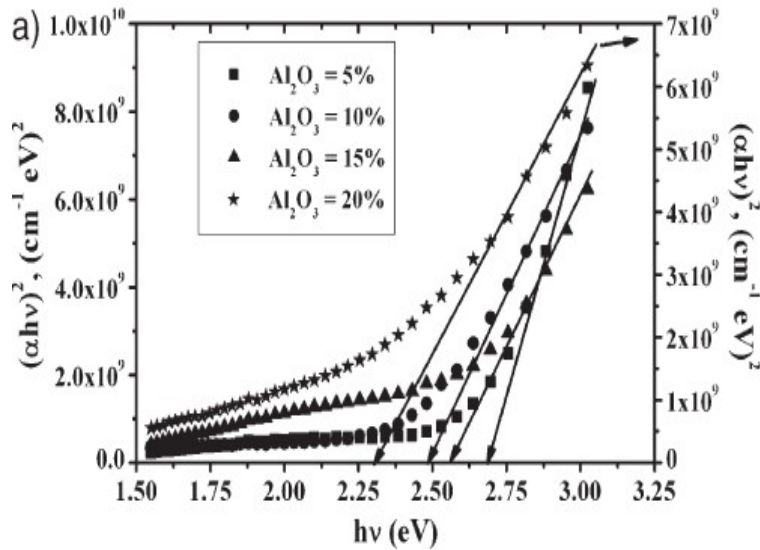
### 2.2 The Electron beam evaporation technique

It is a perfect tool for making vanadium pentoxide thin films such as anti-reflecting, scratch resistant filters and coating lenses[16]. Vanadium pentoxide thin films fabricated by this method were pinhole-free well-adherent and uniform to substrate surface[17]. The freshly prepared vanadium pentoxide films were yellow at room temperature, and when substrate temperature (303 to 603K) was increased, it changed from yellow to orange yellow[17]. Livage et al. reported that

the  $V_2O_5$  films deposited at room temperature were readily dissolved in water giving a clear yellow solution, which confirmed the amorphous nature of the films[18]. In this method when electron beam bombards the target surface it converts kinetic energy of the electron into thermal energy[16]. Co-deposition and sequential configuration, excellent material utilization of film composition and deposition rate can be precisely controlled by electron beam evaporation method. Low energy atom flux can be achieved with minimum impurity by this method [16]. Higher deposition rate may be attained

with a fine structural and morphological control [16]. H.M Ali et al. absorbed the optical bandgap ranges from 1.82 to 2.83

eV, and for different ratios of Al<sub>2</sub>O<sub>3</sub> the bandgap decreases with an increase in annealing temperature[19].



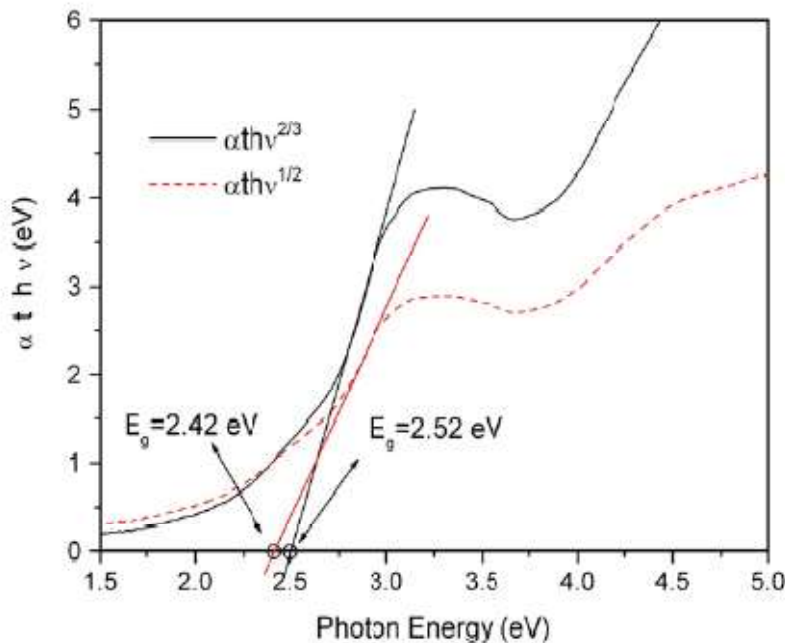
Ref[19]: H.M.Ali and A.M.Abdel Hakeem, Structural and optical properties of electron-beam evaporated Al<sub>2</sub>O<sub>3</sub>-doped V<sub>2</sub>O<sub>5</sub> thin films for various applications Physica Status Solidi A207(2010)132.

Fig:2. Plot of the Urbach energy and the corresponding bandgap of aluminium oxide (Al<sub>2</sub>O<sub>3</sub>)<sub>x</sub> films [19].

2.3 Pulsed laser deposition technique

PLD is a superior method for the preparation of clusters in the range of 10<sup>-9</sup>[9]. Compared to other deposition methods, it is better because in this method V<sub>2</sub>O<sub>5</sub> can be deposited at low temperature (220 °C)[9]. In this technique, from the target a vapour flux is produced by the erosion of a

material due to an array of high energy laser pulses[16].Due to its versatility and flexibility it is mostly applicable in complex oxide thin film deposition[16]. Borek et al. reported the first PLD ablated vanadium monoxide deposition[20]. S.Beke et al. estimated the optical bandgap (2.52 eV) and also the Bohr radius was found to be 4.52 for vanadium pentoxide [9].



Ref[9] : S.Beke, S.Giorgio, L.Korosi, L.Nanai, W.Marine, Structural and optical properties of pulsed laser deposited V<sub>2</sub>O<sub>5</sub> thin films, Thin Solid Films

Fig:3. αthv vs. hv [9].

### III. CONCLUSION

In this paper, orthorhombic structure of vanadium pentoxide thin films coated by different methods namely electron beam evaporation, pulsed laser deposition and thermal evaporation has been investigated. In this case all the developed methods contributed to a wide range of vanadium pentoxide thin film applications, whereas  $V_2O_5$  mainly differed with structural, electrical, and optical properties. The overall SEM study reveals the amorphous nature of  $V_2O_5$  thin film. This review investigated different thicknesses, temperature and bandgaps of  $V_2O_5$  thin film. Regarding the future, the research and applications of  $V_2O_5$  thin film will be focused primarily on gas sensing and catalytic properties.

### REFERENCE

- [1] K. Schneider, M. Lubecka, A. Czapla,  $V_2O_5$  thin films for gas sensor applications, *Sens. Actuators, B* 236 (2016) 970.
- [2] H.N. Cui, V. Teixeira, L.J. Meng, R. Wang, J.Y. Gao, E. Fortunato, Thermo-chromic properties of vanadium oxide films prepared by dc reactive magnetron sputtering, *Thin Solid Films* 516 (2008) 1484.
- [3] P. Deepak Raj, S. Gupta, M. Sridharan, Nanostructured  $V_2O_5$  thin films deposited at low sputtering power, *Mater. Sci. Semicond. Process.* 39 (2015) 426.
- [4] M. Kamalisarvestani, R. Saidur, S. Mekhilef, F.S. Javadi, Performance, materials and coating technologies of thermochromic thin films on smart windows, *Renew. Sustain. Energy Rev.* 26 (2013) 353.
- [5] H. Wang, X. Yi, S. Chen, Low temperature fabrication of vanadium oxide films for uncooled bolometric detectors, *Infrared Phys. Technol.* 47 (2006) 273.
- [6] Claes G. Granqvist, Recent progress in thermo-chromics and electro-chromics: a brief survey, *Thin Solid Films* 614 (2016) 90.
- [7] E.E. Chain, Optical properties of vanadium dioxide and vanadium pentoxide thin films, *Appl. Opt.* 30 (19) (1991) 2782.
- [8] H.M.R. Giannetta, C. Calaza, D.G. Lamas, L. Fonseca, L. Fraigi, Electrical transport properties of  $V_2O_5$  thin films obtained by thermal annealing of layers grown by RF magnetron sputtering at room temperature, *Thin Solid Films* 589 (2015) 730.
- [9] S.Beke, S.Giorgio, L.Korosi, L.Nanai, W.Marine, *Thin Solid Films* 516(2008)4659.
- [10] M.F. Al-Kuhaili, E.E. Khawaja, D.C. Ingram, S.M.A. Durrani, *Thin Solid Films* 460 (2004) 3035.
- [11] R.T. Rajendra Kumar, B. Karunakaran, V. Senthil Kumar, Y.L.Jeyachandran, D. Mangalaraj, S.K. Narayandas, *Mater. Sci. Semicond.Process.* 6 (2003) 543.
- [12] C.V. Ramana, O.M. Hussain, Naidu B. Srinivasalu, C. Julien, M. Balkanski, *Mater. Sci. Eng., B, Solid-State Mater. Adv. Technol.* 52 (1998) 32.
- [13] B.M. Weckhuysen, D.E. Keller, *Catal. Today* 78 (2003) 25.
- [14] Ashvani Kumar, Preetam Singh, Nilesh Kulkarni, Davinder Kaur, *Thin Solid Films* 516(2008)912.
- [15] Sengodan Raja, Gopal subramani, Dinesh Bheeman, Ranjithkumar Rajamani, Chandar Shekar Bellan, *Optik* 127(2016)461.
- [16] Szabolcs Beke, *Thin Solid Films*, 519(2011)1761.
- [17] C V Ramana, O M Hussain, B Srinivasulu Naidu and P J Reddy, *Vacuum* 48(1997)431.
- [18] Livage, J. and Collongues, R., *J.Mater.Sci.and Eng.*, 23(1976)297.
- [19] H.M.Ali and A.M.Abdel Hakeem, *Physica Status Solidi A* 207(2010)132.
- [20] M.Borek, F.Qian, V. Nagabushnam, et al., *Appl. Phys. Lett.* 63(1993)3288.
- [21] R.Santos, J.Loureiro, A.Nogueira, E.Elangovan, J.V.Pinto, Prof.J.P.Veiga, T.Busani, Prof.E.Fortunato, Prof.R.Martins, Prof.I.Ferreira, *Applied Surface Science* 282(2013)590.
- [22] M.A.Sobhan, M.R.Islam, K.A.Khan, *Applied Energy* 64(1999)345.